



RELIABILITY REPORT  
FOR  
MAX6818EAP+  
PLASTIC ENCAPSULATED DEVICES

March 15, 2010

**MAXIM INTEGRATED PRODUCTS**

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## Conclusion

The MAX6818EAP+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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## I. Device Description

### A. General

The MAX6816/MAX6817/MAX6818 are single, dual, and octal switch debouncers that provide clean interfacing of mechanical switches to digital systems. They accept one or more bouncing inputs from a mechanical switch and produce a clean digital output after a short, preset qualification delay. Both the switch opening bounce and the switch closing bounce are removed. Robust switch inputs handle  $\pm 25V$  levels and are  $\pm 15kV$  ESD-protected for use in harsh industrial environments. They feature single-supply operation from +2.7V to +5.5V. Undervoltage lockout circuitry ensures the output is in the correct state upon power-up. The single MAX6816 and dual MAX6817 are offered in SOT packages and require no external components. Their low supply current makes them ideal for use in portable equipment. The MAX6818 octal switch debouncer is designed for data-bus interfacing. The MAX6818 monitors switches and provides a switch change-of-state output (active-low CH), simplifying microprocessor ( $\mu P$ ) polling and interrupts. Additionally, the MAX6818 has three-state outputs controlled by an enable (active-low EN) pin, and is pin-compatible with the LS573 octal latch (except for the active-low CH pin), allowing easy interfacing to a digital data bus.

**II. Manufacturing Information**

A. Description/Function:	±15kV ESD-Protected, Single/Dual/Octal, CMOS Switch Debouncers
B. Process:	S3
C. Number of Device Transistors:	
D. Fabrication Location:	Oregon
E. Assembly Location:	Malaysia, Philippines
F. Date of Initial Production:	July 24, 1998

**III. Packaging Information**

A. Package Type:	20-pin SSOP
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Conductive
E. Bondwire:	Au (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-1601-0051
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	125°C/W
K. Single Layer Theta Jc:	33°C/W
L. Multi Layer Theta Ja:	n/a
M. Multi Layer Theta Jc:	n/a

**IV. Die Information**

A. Dimensions:	74 X 118 mils
B. Passivation:	Si <sub>3</sub> N <sub>4</sub> /SiO <sub>2</sub> (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al/0.5%Cu with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	3.0 microns (as drawn)
F. Minimum Metal Spacing:	3.0 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO <sub>2</sub>
I. Die Separation Method:	Wafer Saw

## V. Quality Assurance Information

- A. Quality Assurance Contacts: Ken Wendel (Director, Reliability Engineering)  
Bryan Preeshl (Managing Director of QA)
- B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.  
0.1% For all Visual Defects.
- C. Observed Outgoing Defect Rate: < 50 ppm
- D. Sampling Plan: Mil-Std-105D

## VI. Reliability Evaluation

### A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate ( $\lambda$ ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 80 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 13.7 \times 10^{-9}$$
$$\lambda = 13.7 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maxim-ic.com/qa/reliability/monitor>. Cumulative monitor data for the S3 Process results in a FIT Rate of 0.04 @ 25C and 0.69 @ 55C (0.8 eV, 60% UCL)

### B. Moisture Resistance Tests

The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

### C. E.S.D. and Latch-Up Testing

The MS21 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2500V per Mil-Std 883 Method 3015.7. Latch-Up testing has shown that this device withstands a current of +/-250mA.

**Table 1**  
Reliability Evaluation Test Results

**MAX6818EAP+**

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
<b>Static Life Test</b> (Note 1)				
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	80	0
<b>Moisture Testing</b> (Note 2)				
HAST	Ta = 130°C RH = 85% Biased Time = 96hrs.	DC Parameters & functionality	77	0
<b>Mechanical Stress</b> (Note 2)				
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data